



Capturing Spatially Varying Anisotropic Reflectance Parameters using Fourier Analysis

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Representing opaque materials

- BRDF 4D function:
 - Incoming light (elevation θ_i & azimuth φ_i)
 - Observation point (elevation θ_o & azimuth φ_o)





Spatially varying material SVBRDF:
+ 2 dimensions: u, v



Representing opaque materials



Representing opaque materials



Related work

	BRDF acquisition	Spatially Var	ing BRDF
		Capture under varying illumination	Gathering sparse and dense measurements
Isotropic	[Matusik <i>et al</i> – 2003]	[Gardner <i>et al</i> – 2003] ★ [Holroyd <i>et al</i> – 2010] ★★	[Ren <i>et al</i> – 2011]
Anisotropic	[Ngan <i>et al</i> – 2005] [Filip <i>et al</i> – 2014]	[Tunwattanapong <i>et al</i> -2013] * * * [Aittala <i>et al</i> -2015] *	[Wang <i>et al</i> – 2008] [Dong <i>et al</i> – 2010]

Lighting system complexity

Easy Average



Related work

[Gardner et al – 2003] Linear Light Source Reflectometry



The linear light source apparatus

Diffuse, Specular intensity, Specular roughness

Rendering

Related work

[Tunwattanapong *et al* – 2013] Acquiring Reflectance and Shape from Continuous Spherical Harmonics Illumination



Acquisition Setup



Reflectance Maps



Rendered 3D Model

Contribution

- Capturing material with a simple setup
 - Easy and cheap to reproduce setup
 - Fast acquisition time
 - Few samples needed (20 used in our example)
 - Simple and flexible
- Dealing with anisotropic Spatially-Varying material
 - No assumption on surrounding pixels
 - Works with high frequency patterns (amulet dataset)







Overview of our technique





0.9

0.8

0.7 0.6

0.5

0.4

0.3 0.2

0.1

0



- Fourier transform
 - Fundamental aver age
 - Har monics complex numbers

$$c_n = \int_0^{2\pi} s(\phi_h) e^{ni\phi_h} \mathrm{d}\phi_h$$

- Frequency domain
 - Argument offset
 - Magnitude contribution



0.9 0.8 Initial estimation of • Anisotropy direction φ_a 0.7 • Normal azimuth φ_n 0.6 0.5 3-step minimization process 0.4 1. Even rank harmonics 0.3 – Anisotropy / Specular 2. First harmonic & fundamental 0.2 - Normal / Diffuse 0.1 3. Fit on signal itself 0 Loop back $3\pi/2$ $\pi/2$ 0 π Light azimuthal angle φ_i

2π

Limitations

- Constrained to almost planar surfaces
 - Shading normal in a limited range variation
- Miss of high specularity or diffuse details
 - 20 samples used Nyquist-Shannon sampling theorm
 - Single exposure images @14bits
- Fresnel term ignored
 - Gazing angles issues

Conclusion & Future work

- Technique for retrieving anisotropic SVBRDF
- Based on Fourier analysis
- Simple capture setup and modular analysis
- Application to **non-planar objects**
- Extension to more advanced anisotropy patterns
- Gathering **similar pixels** to improve accuracy



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Capture setup

- Nikon D7100 camera
 - AF-S Nikkor 18-105mm 1:3.5-5.6G lens
 - Captured in NEF 14 bits
- Rotating arm with light
 - Computer controlled synchronized with camera shoot
- Sample stage

Representation



- Incoming light vector *i*
- Outgoing light vector o
- Half vector $h = \frac{i+o}{\|i+o\|}$
- Anisotropy direction x

BRDF model

Cook-Torrance

$$\mathcal{F}(i, o) = \frac{k_d}{\rho} + \frac{k_s}{\partial_x \partial_y} \frac{F(\cos q_d) G(i, o)}{4 \cos q_i \cos q_o} D\left(\tan^2 q_h \left(\frac{\cos^2 j_h}{\partial_x^2} + \frac{\sin^2 j_h}{\partial_y^2}\right)\right)\right)$$

GGX Isotropic NDF

GGX Anisotropic NDF

$$D(i, o) = \frac{\partial_g^2 C^+(m \times n)}{\rho \cos^4 Q_h (\partial_g^2 + \tan^2 Q_h)^2}$$

$$D(i, \mathbf{0}) = \frac{C^{+}(\mathbf{m} \cdot \mathbf{n})}{\rho \cos^{4} q_{h} \partial_{x} \partial_{y} \left(1 + \tan^{2} q_{h} \left(\frac{\cos^{2} j_{h}}{\partial_{x}^{2}} + \frac{\sin^{2} j_{h}}{\partial_{y}^{2}}\right)\right)^{2}}$$